

## INDUSTRIAL VISIT TO SIFS INDIA, NEW DELHI

*Dronacharya College of Engineering, Gurgaon organized an Industrial Visit to SIFS INDIA, New Delhi on 9th March 2016. 10 students from Information Technology Department visited SIFS India. The aim of this industrial visit was to enable students to learn about image processing techniques, and Cyber Forensics.*

*Ms. Sikshita, Cyber Crime Expert explained about importance of Image Processing, Forensic Science, Protection of Crime Scene, Securing and Isolating the crime scenes, different types of evidences found on a crime scene.*

